

09/981390

09/18/01

Class	Subclass	ISSUE CLASSIFICATION

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PATENT NUMBER

U.S. UTILITY Patent Application

SCANNED <i>KE3</i>	O.I.P.E. <i>LA</i>	PATENT DATE
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APPLICATION NO.	CONT/PRIOR	CLASS	SUBCLASS	ART UNIT	EXAMINER
09/981390	F	250		2878	

APPLICANTS
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Norio Ookubo

TITLE
Scanning probe microscope with probe formed by single conductive material

PTO-2040
12/99

ISSUING CLASSIFICATION

ORIGINAL		CROSS REFERENCE(S)					
CLASS	SUBCLASS	CLASS	SUBCLASS (ONE SUBCLASS PER BLOCK)				
INTERNATIONAL CLASSIFICATION							

☐ Continued on Issue Slip Inside File Jacket

<input type="checkbox"/> TERMINAL DISCLAIMER	DRAWINGS			CLAIMS ALLOWED	
	Sheets Drwg.	Figs. Drwg.	Print Fig.	Total Claims	Print Claim for O.G.
<input type="checkbox"/> The term of this patent subsequent to _____ (date) has been disclaimed. <input type="checkbox"/> The term of this patent shall not extend beyond the expiration date of U.S. Patent. No. _____	_____ (Assistant Examiner) _____ (Date) _____ (Primary Examiner) _____ (Date)			NOTICE OF ALLOWANCE MAILED	
<input type="checkbox"/> The terminal _____ months of this patent have been disclaimed.	_____ (Legal Instruments Examiner) _____ (Date)			ISSUE FEE	
				Amount Due	Date Paid
ISSUE BATCH NUMBER					

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